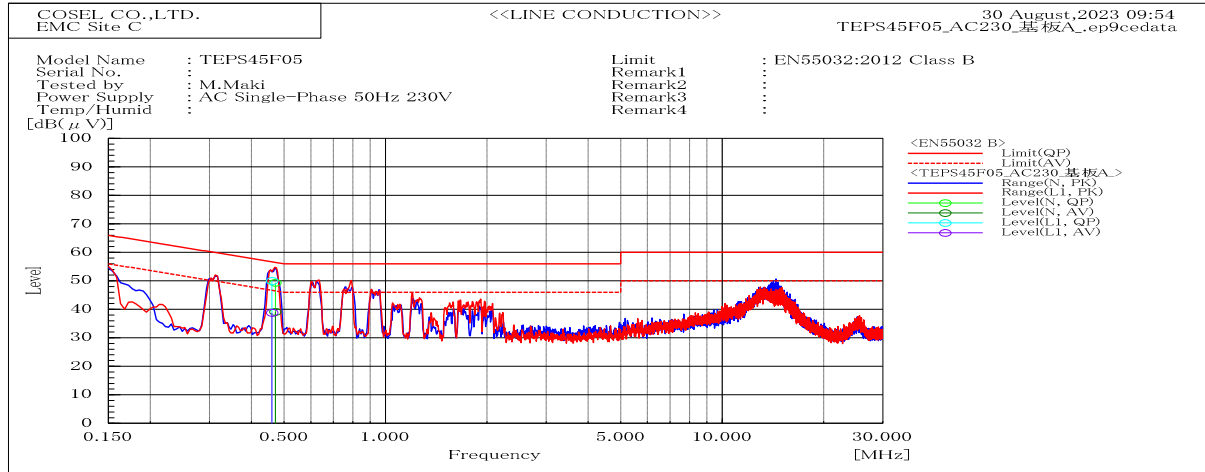
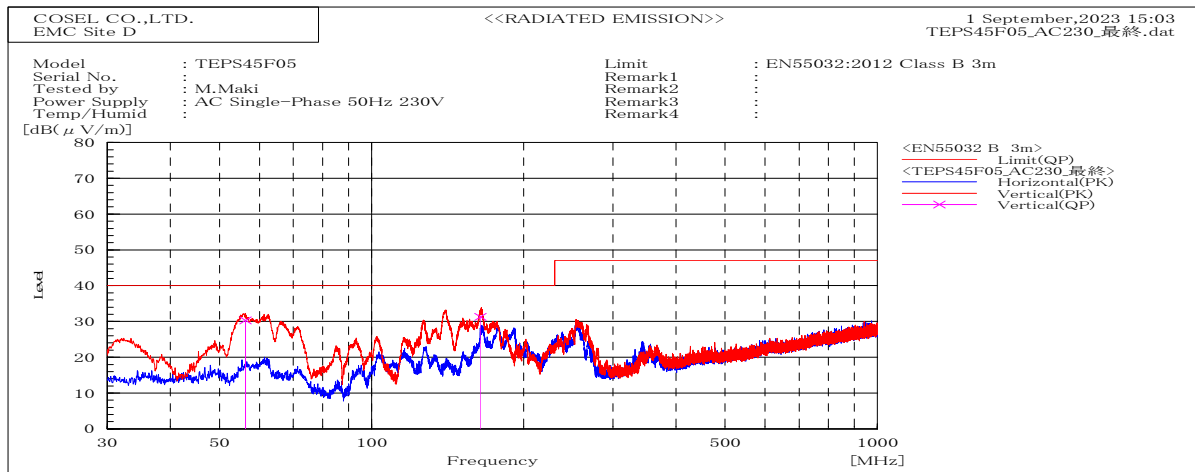


DATA SHEET		Date	12-Oct-23
Model	TEPS45F05	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	M.Maki



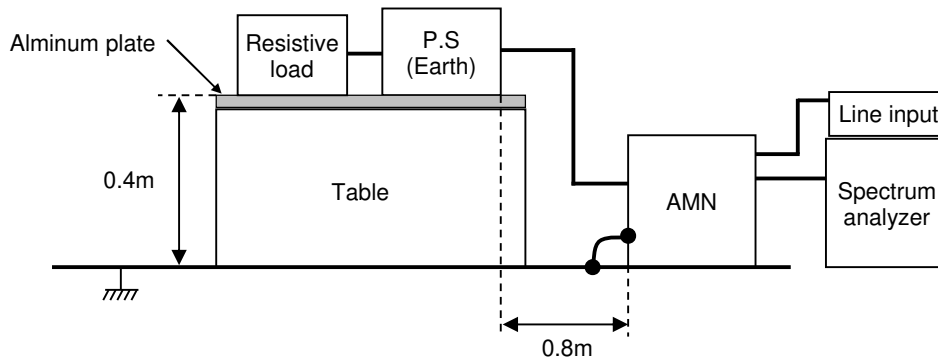
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
0.46	L1	49.9	38.8	56.7	46.7	6.8	7.9	Pass	
0.471	N	49.3	39.1	56.5	46.5	7.2	7.4	Pass	



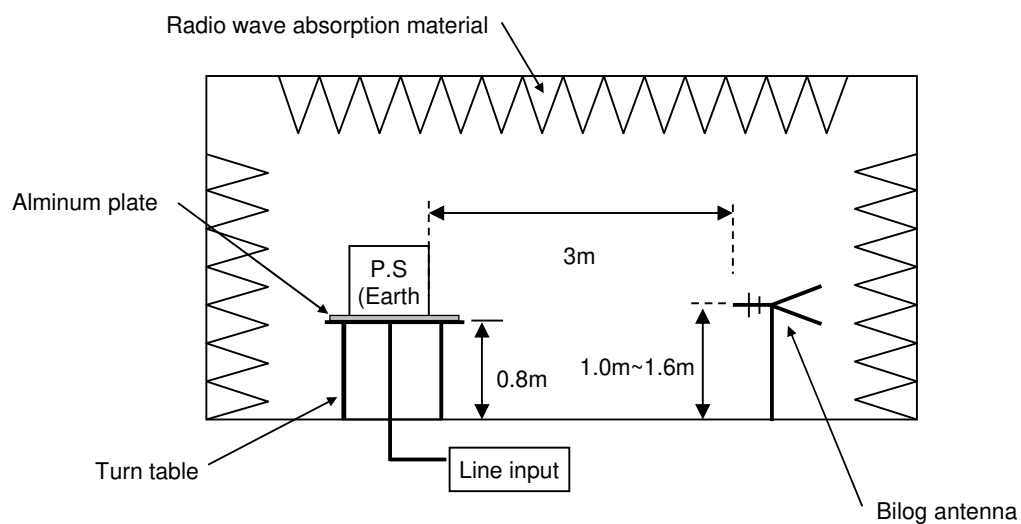
Frequency MHz	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height cm	Angle deg	Remark
			dB(μV/m) QP	dB(μV/m) QP	dB QP				
56.307	V	Stable	30.3	40	9.7	Pass	100.4	336.5	
163.945	V	Stable	31.3	40	8.7	Pass	100.2	359.5	

DATA SHEET		Date	12-Oct-23
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	M.Maki

### 1. Line conduction



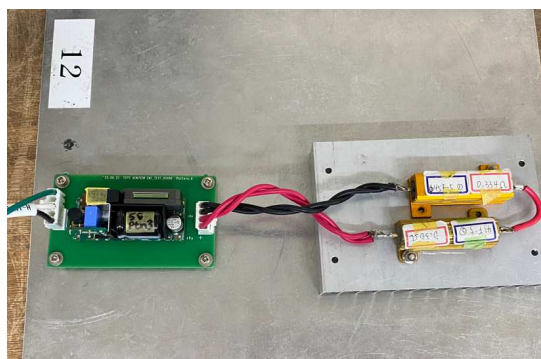
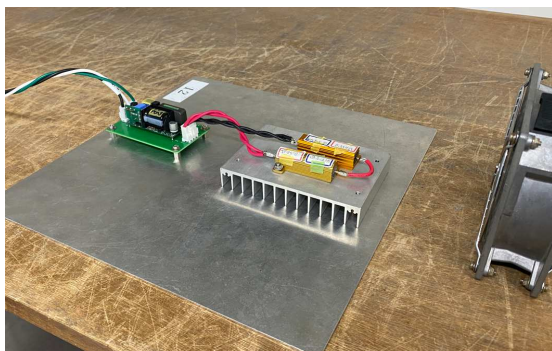
### 2. Radiated emission



## Conditions

Test : EMI  
Model Nam: TEPS45F05

### 1.LINE CONDUCTION



### 2.RADIATED EMISSION

